

LINSPEC

(Information System for Physics, Electronics and Computing)

A training database for learning how to use the INSPEC file

(See database summary sheet **INSPEC** for details on search and display fields which are valid in LINSPEC)

- Subject Coverage**
- Atomic and Molecular Physics
 - Circuit Theory and Circuits
 - Classical Areas of Phenomenology
 - Communications
 - Components, Electronic Devices and Materials
 - Computer Applications
 - Computer Hard- and Software
 - Condensed Matter: Structure, Mechanical Properties, Electronic Structures, Electrical, Magnetic, and Optical Properties
 - Control Technology
 - Cross-Disciplinary Physics and Related Areas of Science and Technology
 - Electromagnetic Fields
 - Engineering Mathematics, Materials Science
 - Fluids, Plasmas, Electric Discharges
 - General and Management Aspects and Applications
 - Geophysics, Astronomy, Astrophysics
 - Information Technology
 - Instrumentation and Special Applications
 - Magnetic and Superconducting Materials and Devices
 - Nuclear Physics
 - Numerical Analysis and Theoretical Computer Topics
 - Office Automation - Communications, Computing
 - Optical Materials and Applications, Electro-Optics and Optoelectronics
 - Physics of Elementary Particles and Fields
 - Power Systems and Applications
 - System and Control Theory
-

File Type Bibliographic, learning

Features	Thesaurus	Controlled Term (/CT), International Patent Classification (/IPC), Physical Properties (/PHP)			
	Alerts (SDIs)	Not available			
	CAS Registry Number [®] Identifiers	<input type="checkbox"/>	Page Images	<input type="checkbox"/>	STN [®] AnaVist [™] <input type="checkbox"/>
	Keep & Share	<input type="checkbox"/>	SLART	<input checked="" type="checkbox"/>	STN Easy [®] <input type="checkbox"/>
	Learning Database	<input checked="" type="checkbox"/>	Structures	<input type="checkbox"/>	

- Record Content**
- Bibliographic information and available abstracts
 - Cited references from journals, books, conference contributions, reports, and other non-conventional literature
-

File Size 100,041 records

Coverage 1898-2006

Updates Closed file

Language English

Database Producer The Institution of Engineering and Technology (IET)
Michael Faraday House, Six Hills Way
Stevenage, Herts SG1 2AY, United Kingdom
Phone: +44 1438/313311
Fax: +44 1438/742840
Email: inspect@theiet.org
Copyright Holder

Database Supplier FIZ Karlsruhe
P.O. Box 2465
76012 Karlsruhe
Germany
Phone: +49 7247 808-555
Fax: +49 7247 808-259
Email: helpdesk@fiz-karlsruhe.de

Sources

- 4,000 Journals
- Reports
- Conferences
- Books
- Dissertations

User Aids

- Online Helps (HELP DIRECTORY lists all help messages available)
- STNGUIDE

Clusters

- LEARNING
[STN Database Clusters](#) information (PDF)

Pricing Enter HELP COST at an arrow prompt.

Sample Records

DISPLAY ALL OF JOURNAL

AN 2006:8692872 LINSPEC
TI Document similarity degree measuring based on compressed sparse matrix vector multiplication technique
AU Huo Hua; Feng Bo-qin (Sch. of Electron. & Inf. English, Xi'an Jiaotong University, China)
SO Mini-Micro Systems (June 2005), vol.26, no.6, p. 988-90, 5 refs.
CODEN: XWJXEH, ISSN: 1000-1220
SICI: 1000-1220(200506)26:6L.988:DSDM;1-X
Published by: Mini-Micro Syst., China, China
DT Journal
TC New Development; Practical; Theoretical
CY China
LA Chinese
AB A novel method to measure document similarity degree based on compressed sparse matrix vector multiplication technique was presented. The design of the method is based on an information retrieval vector model, which has the virtues of being simple and high speed. A compressed sparse matrix vector space is used, in which the zero elements in the vector matrix of documents are not processed while calculating similarity degree and storing data, to reduce the requirements of calculating time and storing space. This method can improve the efficiency of information retrieval system. Simulation experiment indicates that the method can save 38% of the storing space of the conventional inverted index technique based on vector model
CC C7250R Information retrieval techniques; C6130D Document processing techniques; C1110 Algebra
CT document handling; information retrieval; information retrieval systems; matrix multiplication; sparse matrices
ST document similarity degree measurement; compressed sparse matrix vector multiplication; information retrieval vector model; compressed sparse matrix vector space; information retrieval system; inverted index

DISPLAY BIB OF CONFERENCE

AN 2006:8692789 LINSPEC
TI An assessment of the potential for interpretation of CT images by radiological technologists
AU Matsumoto, T.; (Nat. Inst. of Radiol. Sci., Chiba, Japan), Matsumoto, M.; Nagao, K.; Kakinuma, R.; Sone, S.; Furukawa, A.; Fujino, Y.; Wada, S.; Yamamoto, S.; Murao, K.; Endo, M.
SO Proceedings of the SPIE - The International Society for Optical Engineering (2005), vol.5749, no.1, p. 590-600, 14 refs.
CODEN: PSISDG, ISSN: 0277-786X
SICI: 0277-786X(2005)5749:1L.590:APII;1-X
Price: 0277-786X/2005/\$15.00
Published by: SPIE-Int. Society Opt. Eng, USA
Conference: Medical Imaging 2005: Image Perception, Observer Performance, and Technology Assessment, San Diego, CA, USA, 15 Feb. 2005
DT Conference; Conference Article; Journal
TC Practical
CY United States
LA English

In North America

CAS
STN North America
P.O. Box 3012
Columbus, Ohio 43210-0012 U.S.A.

CAS Customer Center:
Phone: 800-753-4227 (North America)
614-447-3700 (worldwide)
Fax: 614-447-3751
Email: help@cas.org
Internet: www.cas.org

In Europe

FIZ Karlsruhe
STN Europe
P.O. Box 2465
76012 Karlsruhe
Germany
Phone: +49-7247-808-555
Fax: +49-7247-808-259
Email: helpdesk@fiz-karlsruhe.de
Internet: www.stn-international.com

In Japan

JAICI (Japan Association for
International Chemical Information)
STN Japan
Nakai Building
6-25-4 Honkomagome, Bunkyo-ku
Tokyo 113-0021, Japan
Phone: +81-3-5978-3601 (Technical Service)
+81-3-5978-3621 (Customer Service)
Fax: +81-3-5978-3600
Email: support@jaici.or.jp (Technical Service)
customer@jaici.or.jp (Customer Service)
Internet: www.jaici.or.jp